

Notice of References Cited

Application/Control No.

10/507,258

Applicant(s)/Patent Under
Reexamination
PEZZOTTI, GIUSEPPE

Examiner

BOBBY RAMDHANIE

Art Unit

1797

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a))
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